

**Search Notes**

Application/Control No.

10/524,389

Examiner

Lan Nguyen

Applicant(s)/Patent under  
Reexamination

BAECHLE ET AL.

Art Unit

3683

**SEARCHED**

Class	Subclass	Date	Examiner
303	113.1	3/8/2007	XLN
	113.2		
	113.5		
	115.4		
	116.1		
	119.1		
	119.3		
188	352		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text included	3/8/2007	XLN